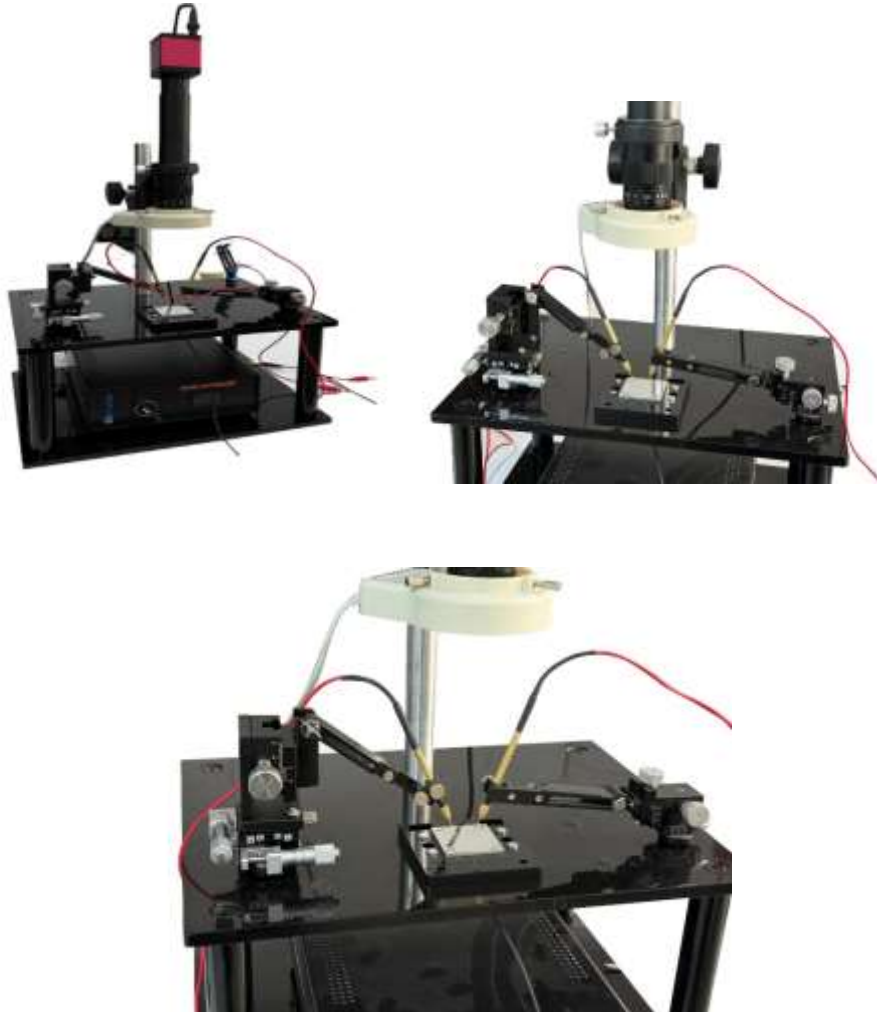




PROBE STATION

I-V AND THIN FILM TRANSISTOR APPLICATIONS



PROBE STATION can be used for current-voltage characteristics of electronic devices such as solar cell, photodiode, sensor and thin film transistors. Probe station is designed according to below technical properties.

Technical Datasheet

XYZ manipulators (2 or 3)

Vacuum chuck

Temperature chuck

Temperature controller

Microscope for thin film transistor applications

High resolution camera: 5 MPA

Magnification: 130X

Monitor

Probe pin: Spring pin